



Novel Techniques for Detecting Radiation and Radioactive Contamination

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Message from the Guest Editor

This Special Issue is launched to collect original research showing cutting-edge techniques for radiation detection and dosimetry that match the future needs of society over the coming generations. Envisioned topics are as follows:

New developments of:

- Photon/electron dosimetry
- Neutron dosimetry
- Protons/heavy ions dosimetry
- Micro and nano-dosimetry
- Pulsed field dosimetry
- Computational dosimetry

New detectors using:

- Scintillation
- Semiconductor
- Electron paramagnetic/spin resonance
- Luminescence
- Nuclear track
- Fricke and polymer gel
- Radiochromic complex
- Superheated emulsions
- Other phenomena/materials

New approaches to:

- Medical dose verification
- Radiological/nuclear emergency dosimetry
- Assessment of external/internal exposure
- Monitoring of environmental radiation/radioactivity
- Space and aviation dosimetry
- Retrospective dosimetry/dating





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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